Welcome to E-XFL.COM

What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "Embedded - Microcontrollers"

Details	
Product Status	Active
Core Processor	ARM® Cortex®-M0
Core Size	32-Bit Single-Core
Speed	48MHz
Connectivity	CANbus, HDMI-CEC, I²C, IrDA, LINbus, SPI, UART/USART, USB
Peripherals	DMA, I²S, POR, PWM, WDT
Number of I/O	37
Program Memory Size	128KB (128K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	16K x 8
Voltage - Supply (Vcc/Vdd)	1.65V ~ 3.6V
Data Converters	A/D 10x12b; D/A 2x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	48-LQFP
Supplier Device Package	48-LQFP (7x7)
Purchase URL	https://www.e-xfl.com/product-detail/stmicroelectronics/stm32f072cbt6

List of tables

Table 1. Device summary . . . 1
Table 2. STM32F072x8/xB family device features and peripheral counts . . . 11
Table 3. Temperature sensor calibration values . . . 18
Table 4. Internal voltage reference calibration values . . . 19
Table 5. Capacitive sensing GPIOs available on STM32F072x8/xB devices . . . 20
Table 6. Number of capacitive sensing channels available on STM32F072x8/xB devices . . . 21
Table 7. Timer feature comparison . . . 21
Table 8. Comparison of I^2C analog and digital filters . . . 24
Table 9. STM32F072x8/xB I^2C implementation . . . 25
Table 10. STM32F072x8/xB USART implementation . . . 25
Table 11. STM32F072x8/xB SPI/I^2S implementation . . . 26
Table 12. Legend/abbreviations used in the pinout table . . . 33
Table 13. STM32F072x8/xB pin definitions . . . 33
Table 14. Alternate functions selected through GPIOA_AFR registers for port A . . . 41
Table 15. Alternate functions selected through GPIOB_AFR registers for port B . . . 42
Table 16. Alternate functions selected through GPIOC_AFR registers for port C . . . 43
Table 17. Alternate functions selected through GPIOD_AFR registers for port D . . . 43
Table 18. Alternate functions selected through GPIOE_AFR registers for port E . . . 44
Table 19. Alternate functions available on port F . . . 44
Table 20. STM32F072x8/xB peripheral register boundary addresses . . . 46
Table 21. Voltage characteristics . . . 51
Table 22. Current characteristics . . . 52
Table 23. Thermal characteristics . . . 52
Table 24. General operating conditions . . . 53
Table 25. Operating conditions at power-up / power-down . . . 54
Table 26. Embedded reset and power control block characteristics . . . 54
Table 27. Programmable voltage detector characteristics . . . 54
Table 28. Embedded internal reference voltage . . . 55
Table 29. Typical and maximum current consumption from V_{DD} supply at V_{DD} = 3.6 V . . . 56
Table 30. Typical and maximum current consumption from the V_{DDA} supply . . . 58
Table 31. Typical and maximum consumption in Stop and Standby modes . . . 59
Table 32. Typical and maximum current consumption from the V_{BAT} supply . . . 60
Table 33. Typical current consumption, code executing from Flash memory, running from HSE 8 MHz crystal . . . 61
Table 34. Switching output I/O current consumption . . . 63
Table 35. Peripheral current consumption . . . 64
Table 36. Low-power mode wakeup timings . . . 66
Table 37. High-speed external user clock characteristics . . . 66
Table 38. Low-speed external user clock characteristics . . . 67
Table 39. HSE oscillator characteristics . . . 68
Table 40. LSE oscillator characteristics (f_{LSE} = 32.768 kHz) . . . 69
Table 41. HSI oscillator characteristics . . . 71
Table 42. HSI14 oscillator characteristics . . . 72
Table 43. HSI48 oscillator characteristics . . . 73
Table 44. LSI oscillator characteristics . . . 74
Table 45. PLL characteristics . . . 74
Table 46. Flash memory characteristics . . . 74

List of figures

Figure 1. Block diagram . . . 12
Figure 2. Clock tree . . . 16
Figure 3. UFBGA100 package pinout . . . 28
Figure 4. LQFP100 package pinout . . . 29
Figure 5. UFBGA64 package pinout . . . 30
Figure 6. LQFP64 package pinout . . . 31
Figure 7. LQFP48 package pinout . . . 31
Figure 8. UFQFPN48 package pinout . . . 32
Figure 9. WLCSP49 package pinout . . . 32
Figure 10. STM32F072xB memory map . . . 45
Figure 11. Pin loading conditions . . . 48
Figure 12. Pin input voltage . . . 48
Figure 13. Power supply scheme . . . 49
Figure 14. Current consumption measurement scheme . . . 50
Figure 15. High-speed external clock source AC timing diagram . . . 67
Figure 16. Low-speed external clock source AC timing diagram . . . 67
Figure 17. Typical application with an 8 MHz crystal . . . 69
Figure 18. Typical application with a 32.768 kHz crystal . . . 70
Figure 19. HSI oscillator accuracy characterization results for soldered parts . . . 71
Figure 20. HSI14 oscillator accuracy characterization results . . . 72
Figure 21. HSI48 oscillator accuracy characterization results . . . 73
Figure 22. TC and TTa I/O input characteristics . . . 80
Figure 23. Five volt tolerant (FT and FTf) I/O input characteristics . . . 80
Figure 24. I/O AC characteristics definition . . . 83
Figure 25. Recommended NRST pin protection . . . 84
Figure 26. ADC accuracy characteristics . . . 87
Figure 27. Typical connection diagram using the ADC . . . 87
Figure 28. 12-bit buffered / non-buffered DAC . . . 89
Figure 29. Maximum V_{REFINT} scaler startup time from power down . . . 91
Figure 30. SPI timing diagram - slave mode and CPHA = 0 . . . 95
Figure 31. SPI timing diagram - slave mode and CPHA = 1 . . . 95
Figure 32. SPI timing diagram - master mode . . . 96
Figure 33. I^2S slave timing diagram (Philips protocol) . . . 97
Figure 34. I^2S master timing diagram (Philips protocol) . . . 98
Figure 35. UFBGA100 package outline . . . 100
Figure 36. Recommended footprint for UFBGA100 package . . . 101
Figure 37. UFBGA100 package marking example . . . 102
Figure 38. LQFP100 package outline . . . 103
Figure 39. Recommended footprint for LQFP100 package . . . 104
Figure 40. LQFP100 package marking example . . . 105
Figure 41. UFBGA64 package outline . . . 106
Figure 42. Recommended footprint for UFBGA64 package . . . 107
Figure 43. UFBGA64 package marking example . . . 108
Figure 44. LQFP64 package outline . . . 109
Figure 45. Recommended footprint for LQFP64 package . . . 110
Figure 46. LQFP64 package marking example . . . 111
Figure 47. WLCSP49 package outline . . . 112
Figure 48. WLCSP49 package marking example . . . 114

Figure 49. LQFP48 package outline . . . 115
Figure 50. Recommended footprint for LQFP48 package . . . 116
Figure 51. LQFP48 package marking example . . . 117
Figure 52. UFQFPN48 package outline . . . 118
Figure 53. Recommended footprint for UFQFPN48 package . . . 119
Figure 54. UFQFPN48 package marking example . . . 120
Figure 55. LQFP64 P_D max versus T_A . . . 123

1 Introduction

This datasheet provides the ordering information and mechanical device characteristics of the STM32F072x8/xB microcontrollers.

This document should be read in conjunction with the STM32F0xxxx reference manual (RM0091). The reference manual is available from the STMicroelectronics website *www.st.com*.

For information on the ARM® Cortex®-M0 core, please refer to the Cortex®-M0 Technical Reference Manual, available from the www.arm.com website.

Table 6. Number of capacitive sensing channels available on STM32F072x8/xB devices

Analog I/O group	Number of capacitive sensing channels		
	STM32F072Vx	STM32F072Rx	STM32F072Cx
G1	3	3	3
G2	3	3	3
G3	3	3	2
G4	3	3	3
G5	3	3	3
G6	3	3	3
G7	3	0	0
G8	3	0	0
Number of capacitive sensing channels	24	18	17

3.14 Timers and watchdogs

The STM32F072x8/xB devices include up to six general-purpose timers, two basic timers and an advanced control timer.

Table 7 compares the features of the different timers.

Table 7. Timer feature comparison

Timer type	Timer	Counter resolution	Counter type	Prescaler factor	DMA request generation	Capture/compare channels	Complementary outputs
Advanced control	TIM1	16-bit	Up, down, up/down	integer from 1 to 65536	Yes	4	3
General purpose	TIM2	32-bit	Up, down, up/down	integer from 1 to 65536	Yes	4	-
	TIM3	16-bit	Up, down, up/down	integer from 1 to 65536	Yes	4	-
	TIM14	16-bit	Up	integer from 1 to 65536	No	1	-
	TIM15	16-bit	Up	integer from 1 to 65536	Yes	2	1
	TIM16 TIM17	16-bit	Up	integer from 1 to 65536	Yes	1	1
Basic	TIM6 TIM7	16-bit	Up	integer from 1 to 65536	Yes	-	-

Figure 8. UFQFPN48 package pinout

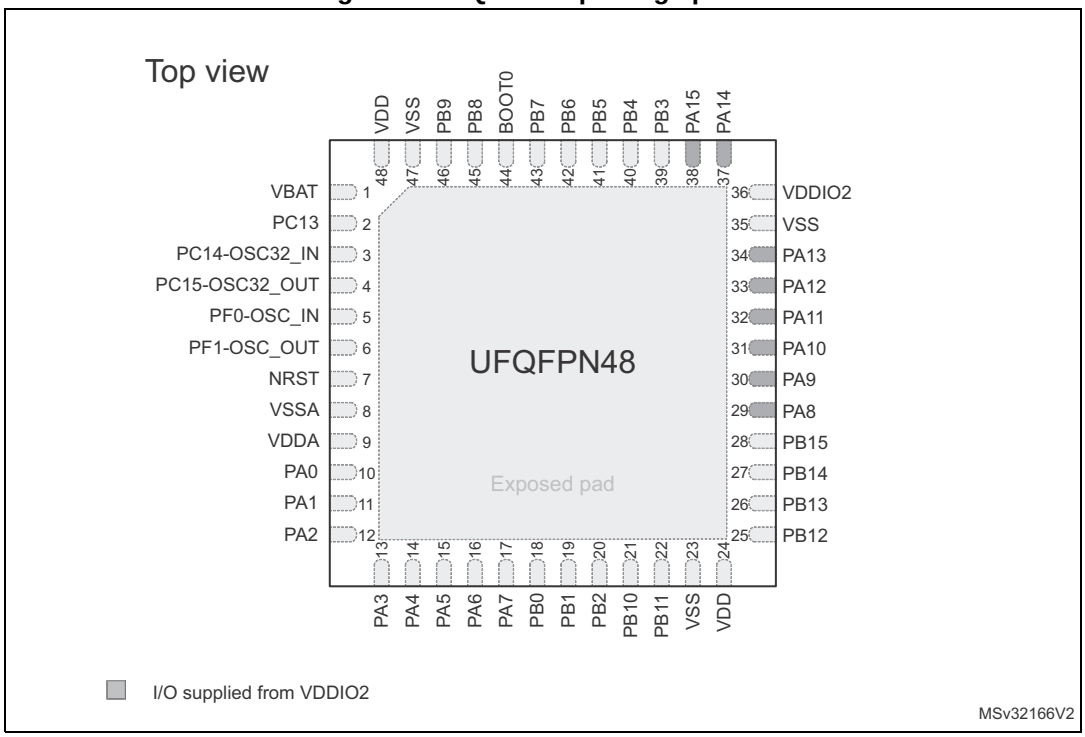
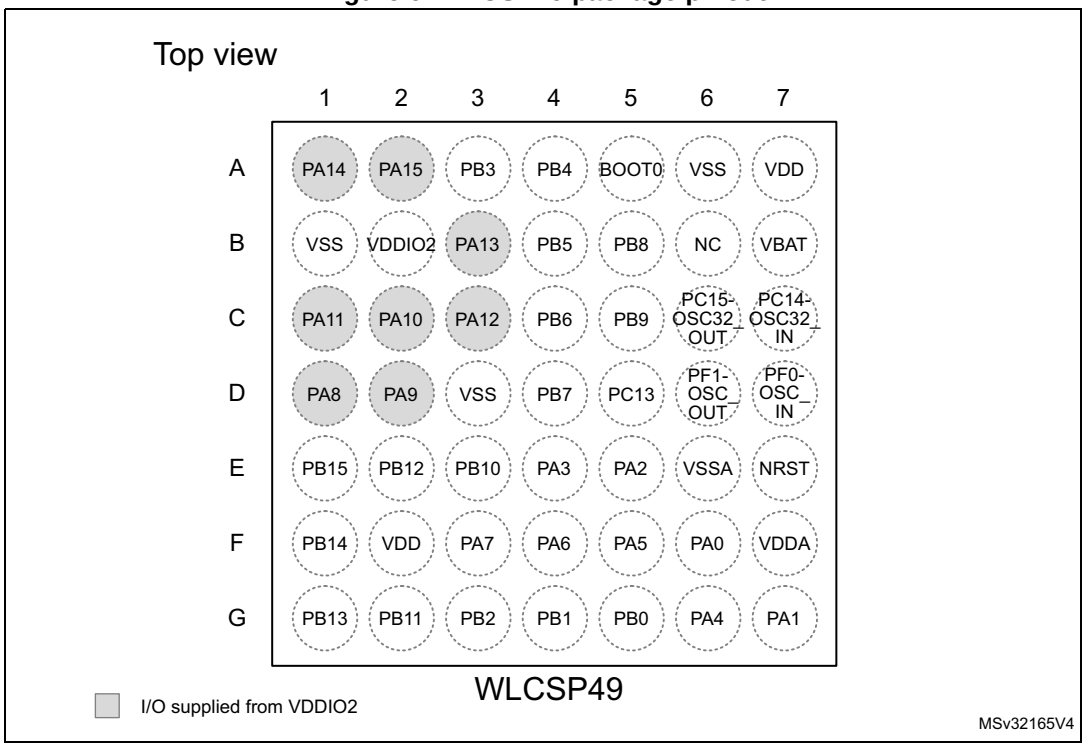


Figure 9. WLCSP49 package pinout



1. The above figure shows the package in top view, changing from bottom view in the previous document versions.

Table 16. Alternate functions selected through GPIOC_AFR registers for port C

Pin name	AF0	AF1
PC0	EVENTOUT	-
PC1	EVENTOUT	-
PC2	EVENTOUT	SPI2_MISO, I2S2_MCK
PC3	EVENTOUT	SPI2_MOSI, I2S2_SD
PC4	EVENTOUT	USART3_TX
PC5	TSC_G3_IO1	USART3_RX
PC6	TIM3_CH1	-
PC7	TIM3_CH2	-
PC8	TIM3_CH3	-
PC9	TIM3_CH4	-
PC10	USART4_TX	USART3_TX
PC11	USART4_RX	USART3_RX
PC12	USART4_CK	USART3_CK
PC13	-	-
PC14	-	-
PC15	-	-

Table 17. Alternate functions selected through GPIOD_AFR registers for port D

Pin name	AF0	AF1
PD0	CAN_RX	SPI2_NSS, I2S2_WS
PD1	CAN_TX	SPI2_SCK, I2S2_CK
PD2	TIM3_ETR	USART3_RTS
PD3	USART2_CTS	SPI2_MISO, I2S2_MCK
PD4	USART2_RTS	SPI2_MOSI, I2S2_SD
PD5	USART2_TX	-
PD6	USART2_RX	-
PD7	USART2_CK	-
PD8	USART3_TX	-
PD9	USART3_RX	-
PD10	USART3_CK	-
PD11	USART3_CTS	-
PD12	USART3_RTS	TSC_G8_IO1
PD13	-	TSC_G8_IO2
PD14	-	TSC_G8_IO3
PD15	CRS_SYNC	TSC_G8_IO4

5 Memory mapping

To the difference of STM32F072xB memory map in *Figure 10*, the two bottom code memory spaces of STM32F072x8 end at 0x0000 FFFF and 0x0800 FFFF, respectively.

Figure 10. STM32F072xB memory map

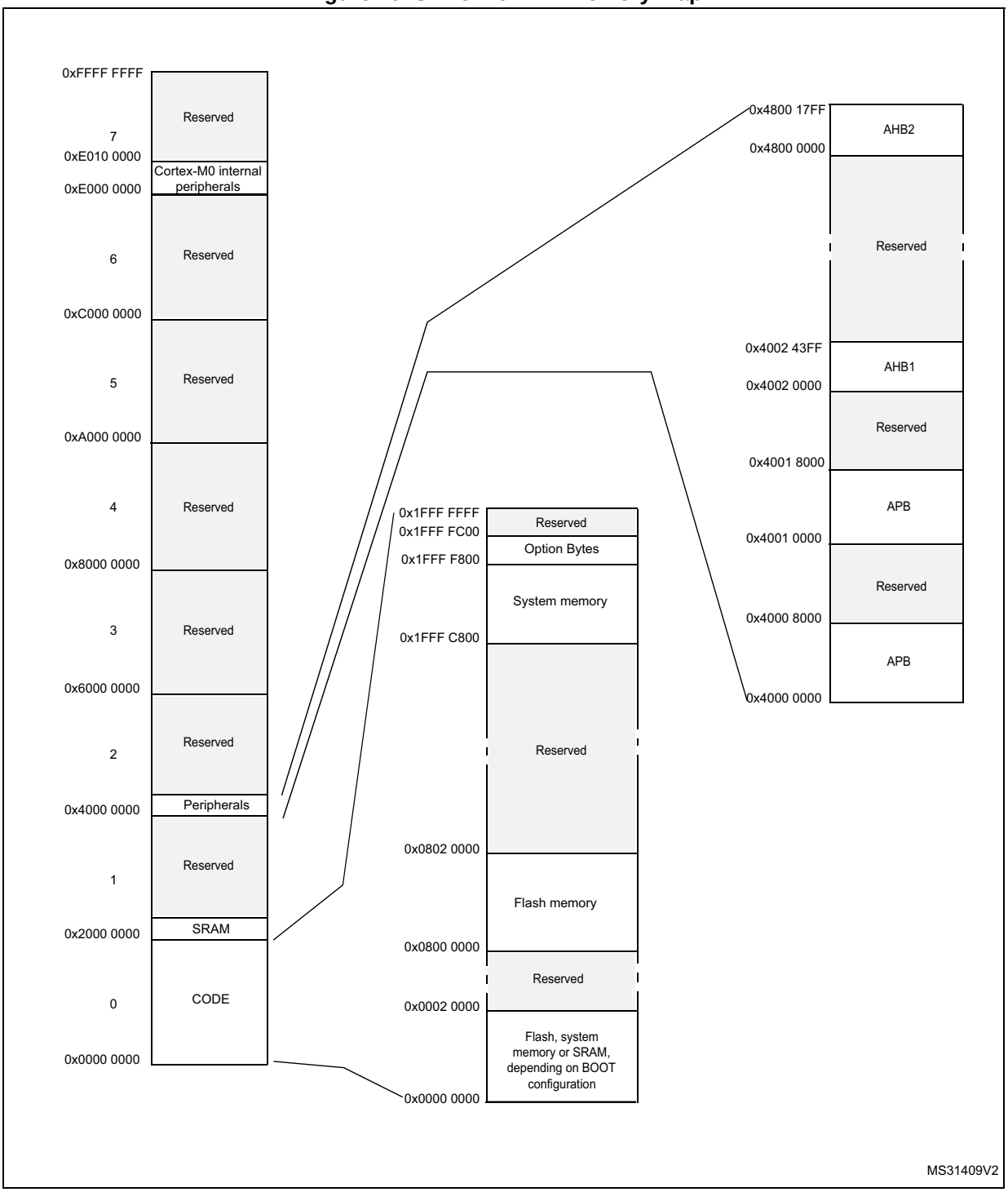


Table 20. STM32F072x8/xB peripheral register boundary addresses (continued)

Bus	Boundary address	Size	Peripheral
APB	0x4000 7C00 - 0x4000 7FFF	1 KB	Reserved
	0x4000 7800 - 0x4000 7BFF	1 KB	CEC
	0x4000 7400 - 0x4000 77FF	1 KB	DAC
	0x4000 7000 - 0x4000 73FF	1 KB	PWR
	0x4000 6C00 - 0x4000 6FFF	1 KB	CRS
	0x4000 6800 - 0x4000 6BFF	1 KB	Reserved
	0x4000 6400 - 0x4000 67FF	1 KB	BxCAN
	0x4000 6000 - 0x4000 63FF	1 KB	USB/CAN RAM
	0x4000 5C00 - 0x4000 5FFF	1 KB	USB
	0x4000 5800 - 0x4000 5BFF	1 KB	I2C2
	0x4000 5400 - 0x4000 57FF	1 KB	I2C1
	0x4000 5000 - 0x4000 53FF	1 KB	Reserved
	0x4000 4C00 - 0x4000 4FFF	1 KB	USART4
	0x4000 4800 - 0x4000 4BFF	1 KB	USART3
	0x4000 4400 - 0x4000 47FF	1 KB	USART2
	0x4000 3C00 - 0x4000 43FF	2 KB	Reserved
	0x4000 3800 - 0x4000 3BFF	1 KB	SPI2
	0x4000 3400 - 0x4000 37FF	1 KB	Reserved
	0x4000 3000 - 0x4000 33FF	1 KB	IWDG
	0x4000 2C00 - 0x4000 2FFF	1 KB	WWDG
	0x4000 2800 - 0x4000 2BFF	1 KB	RTC
	0x4000 2400 - 0x4000 27FF	1 KB	Reserved
	0x4000 2000 - 0x4000 23FF	1 KB	TIM14
	0x4000 1800 - 0x4000 1FFF	2 KB	Reserved
	0x4000 1400 - 0x4000 17FF	1 KB	TIM7
	0x4000 1000 - 0x4000 13FF	1 KB	TIM6
	0x4000 0800 - 0x4000 0FFF	2 KB	Reserved
	0x4000 0400 - 0x4000 07FF	1 KB	TIM3
	0x4000 0000 - 0x4000 03FF	1 KB	TIM2

6 Electrical characteristics

6.1 Parameter conditions

Unless otherwise specified, all voltages are referenced to V_{SS}.

6.1.1 Minimum and maximum values

Unless otherwise specified, the minimum and maximum values are guaranteed in the worst conditions of ambient temperature, supply voltage and frequencies by tests in production on 100% of the devices with an ambient temperature at T_A = 25 °C and T_A = $T_A$max (given by the selected temperature range).

Data based on characterization results, design simulation and/or technology characteristics are indicated in the table footnotes and are not tested in production. Based on characterization, the minimum and maximum values refer to sample tests and represent the mean value plus or minus three times the standard deviation (mean ±3σ).

6.1.2 Typical values

Unless otherwise specified, typical data are based on T_A = 25 °C, V_{DD} = V_{DDA} = 3.3 V. They are given only as design guidelines and are not tested.

Typical ADC accuracy values are determined by characterization of a batch of samples from a standard diffusion lot over the full temperature range, where 95% of the devices have an error less than or equal to the value indicated (mean ±2σ).

6.1.3 Typical curves

Unless otherwise specified, all typical curves are given only as design guidelines and are not tested.

6.1.4 Loading capacitor

The loading conditions used for pin parameter measurement are shown in *Figure 11*.

6.1.5 Pin input voltage

The input voltage measurement on a pin of the device is described in *Figure 12*.

Figure 11. Pin loading conditions

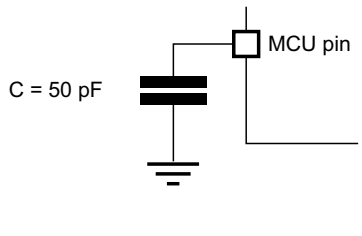


Figure 12. Pin input voltage

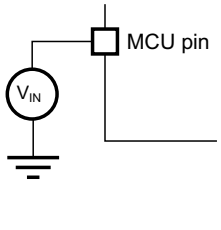


Table 31. Typical and maximum consumption in Stop and Standby modes

Sym-bol	Para-meter	Conditions		Typ @V_{DD} (V_{DD} = V_{DDA})						Max(1)			Unit
				2.0 V	2.4 V	2.7 V	3.0 V	3.3 V	3.6 V	T_A = 25 °C	T_A = 85 °C	T_A = 105 °C	
I_{DD}	Supply current in Stop mode	Regulator in run mode, all oscillators OFF		15.4	15.5	15.6	15.7	15.8	15.9	23(2)	49	68(2)	µA
		Regulator in low-power mode, all oscillators OFF		3.2	3.3	3.4	3.5	3.6	3.7	8(2)	33	51(2)	
	Supply current in Standby mode	LSI ON and IWDG ON		0.8	1.0	1.1	1.2	1.3	1.4	-	-	-	
		LSI OFF and IWDG OFF		0.6	0.7	0.9	0.9	1.0	1.1	2.1(2)	2.6	3.1(2)	
I_{DDA}	Supply current in Stop mode	V_{DDA} monitoring ON	Regulator in run mode, all oscillators OFF	2.1	2.2	2.3	2.5	2.6	2.8	3.5(2)	3.6	4.6(2)	
			Regulator in low-power mode, all oscillators OFF	2.1	2.2	2.3	2.5	2.6	2.8	3.5(2)	3.6	4.6(2)	
	Supply current in Standby mode		LSI ON and IWDG ON	2.5	2.7	2.8	3.0	3.2	3.5	-	-	-	
			LSI OFF and IWDG OFF	1.9	2.1	2.2	2.3	2.5	2.6	3.5(2)	3.6	4.6(2)	
	Supply current in Stop mode	V_{DDA} monitoring OFF	Regulator in run mode, all oscillators OFF	1.3	1.3	1.4	1.4	1.5	1.5	-	-	-	
			Regulator in low-power mode, all oscillators OFF	1.3	1.3	1.4	1.4	1.5	1.5	-	-	-	
	Supply current in Standby mode		LSI ON and IWDG ON	1.7	1.8	1.9	2.0	2.1	2.2	-	-	-	
			LSI OFF and IWDG OFF	1.2	1.2	1.2	1.3	1.3	1.4	-	-	-	

1. Data based on characterization results, not tested in production unless otherwise specified.
2. Data based on characterization results and tested in production (using one common test limit for sum of I_{DD} and I_{DDA}).

Table 34. Switching output I/O current consumption

Symbol	Parameter	Conditions[1]	I/O toggling frequency (f_{SW})	Typ	Unit
I_{SW}	I/O current consumption	V_{DDIOx} = 3.3 V C =C_{INT}	4 MHz	0.07	mA
			8 MHz	0.15	
			16 MHz	0.31	
			24 MHz	0.53	
			48 MHz	0.92	
		V_{DDIOx} = 3.3 V C_{EXT} = 0 pF C = C_{INT} + C_{EXT}+ C_S	4 MHz	0.18	
			8 MHz	0.37	
			16 MHz	0.76	
			24 MHz	1.39	
			48 MHz	2.188	
		V_{DDIOx} = 3.3 V C_{EXT} = 10 pF C = C_{INT} + C_{EXT}+ C_S	4 MHz	0.32	
			8 MHz	0.64	
			16 MHz	1.25	
			24 MHz	2.23	
			48 MHz	4.442	
		V_{DDIOx} = 3.3 V C_{EXT} = 22 pF C = C_{INT} + C_{EXT}+ C_S	4 MHz	0.49	
			8 MHz	0.94	
			16 MHz	2.38	
			24 MHz	3.99	
		V_{DDIOx} = 3.3 V C_{EXT} = 33 pF C = C_{INT} + C_{EXT}+ C_S	4 MHz	0.64	
			8 MHz	1.25	
			16 MHz	3.24	
			24 MHz	5.02	
		V_{DDIOx} = 3.3 V C_{EXT} = 47 pF C = C_{INT} + C_{EXT}+ C_S C = C_{int}	4 MHz	0.81	
			8 MHz	1.7	
			16 MHz	3.67	
		V_{DDIOx} = 2.4 V C_{EXT} = 47 pF C = C_{INT} + C_{EXT}+ C_S C = C_{int}	4 MHz	0.66	
			8 MHz	1.43	
			16 MHz	2.45	
			24 MHz	4.97	

1. C_S = 7 pF (estimated value).

High-speed external clock generated from a crystal/ceramic resonator

The high-speed external (HSE) clock can be supplied with a 4 to 32 MHz crystal/ceramic resonator oscillator. All the information given in this paragraph are based on design simulation results obtained with typical external components specified in *Table 39*. In the application, the resonator and the load capacitors have to be placed as close as possible to the oscillator pins in order to minimize output distortion and startup stabilization time. Refer to the crystal resonator manufacturer for more details on the resonator characteristics (frequency, package, accuracy).

Table 39. HSE oscillator characteristics

Symbol	Parameter	Conditions(1)	Min(2)	Typ	Max(2)	Unit
f_{OSC_IN}	Oscillator frequency	-	4	8	32	MHz
R_F	Feedback resistor	-	-	200	-	kΩ
I_{DD}	HSE current consumption	During startup(3)	-	-	8.5	mA
		V_{DD} = 3.3 V, Rm = 30 Ω, CL = 10 pF@8 MHz	-	0.4	-	
		V_{DD} = 3.3 V, Rm = 45 Ω, CL = 10 pF@8 MHz	-	0.5	-	
		V_{DD} = 3.3 V, Rm = 30 Ω, CL = 5 pF@32 MHz	-	0.8	-	
		V_{DD} = 3.3 V, Rm = 30 Ω, CL = 10 pF@32 MHz	-	1	-	
		V_{DD} = 3.3 V, Rm = 30 Ω, CL = 20 pF@32 MHz	-	1.5	-	
g_m	Oscillator transconductance	Startup	10	-	-	mA/V
$t_{SU(HSE)}$(4)	Startup time	V_{DD} is stabilized	-	2	-	ms

1. Resonator characteristics given by the crystal/ceramic resonator manufacturer.
2. Guaranteed by design, not tested in production.
3. This consumption level occurs during the first 2/3 of the $t_{SU(HSE)}$ startup time
4. $t_{SU(HSE)}$ is the startup time measured from the moment it is enabled (by software) to a stabilized 8 MHz oscillation is reached. This value is measured for a standard crystal resonator and it can vary significantly with the crystal manufacturer

For C_{L1} and C_{L2}, it is recommended to use high-quality external ceramic capacitors in the 5 pF to 20 pF range (Typ.), designed for high-frequency applications, and selected to match the requirements of the crystal or resonator (see *Figure 17*). C_{L1} and C_{L2} are usually the same size. The crystal manufacturer typically specifies a load capacitance which is the series combination of C_{L1} and C_{L2}. PCB and MCU pin capacitance must be included (10 pF can be used as a rough estimate of the combined pin and board capacitance) when sizing C_{L1} and C_{L2}.

Note: For information on selecting the crystal, refer to the application note AN2867 “Oscillator design guide for ST microcontrollers” available from the ST website www.st.com.

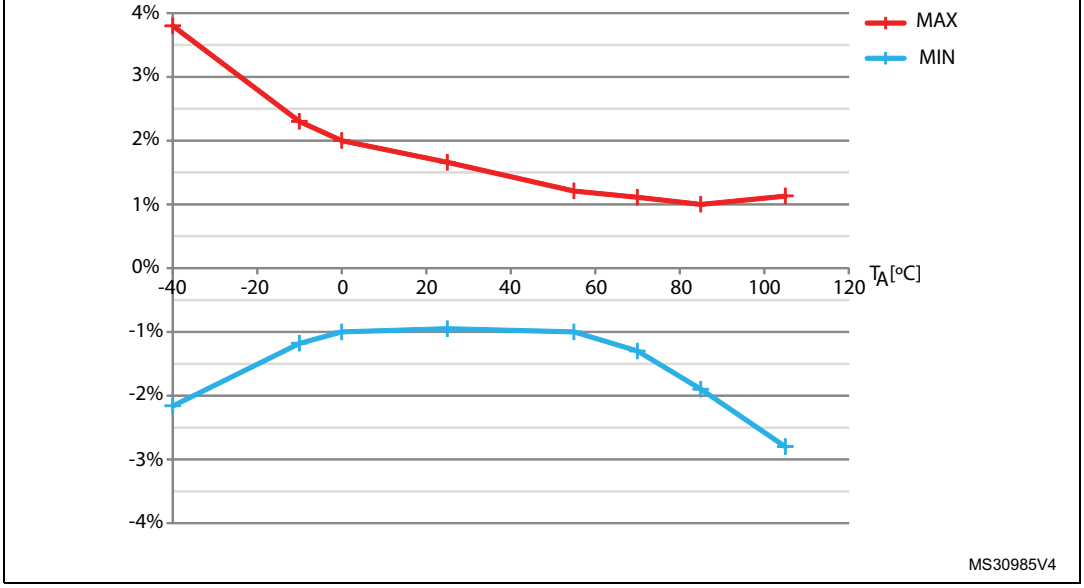
High-speed internal (HSI) RC oscillator

Table 41. HSI oscillator characteristics(1)

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
f_{HSI}	Frequency	-	-	8	-	MHz
TRIM	HSI user trimming step	-	-	-	1(2)	%
$DuCy_{(HSI)}$	Duty cycle	-	45(2)	-	55(2)	%
ACC_{HSI}	Accuracy of the HSI oscillator	T_A = -40 to 105°C	-2.8(3)	-	3.8(3)	%
		T_A = -10 to 85°C	-1.9(3)	-	2.3(3)	
		T_A = 0 to 85°C	-1.9(3)	-	2(3)	
		T_A = 0 to 70°C	-1.3(3)	-	2(3)	
		T_A = 0 to 55°C	-1(3)	-	2(3)	
		T_A = 25°C(4)	-1	-	1	
$t_{su(HSI)}$	HSI oscillator startup time	-	1(2)	-	2(2)	µs
$I_{DDA(HSI)}$	HSI oscillator power consumption	-	-	80	100(2)	µA

1. V_{DDA} = 3.3 V, T_A = -40 to 105°C unless otherwise specified.
2. Guaranteed by design, not tested in production.
3. Data based on characterization results, not tested in production.
4. Factory calibrated, parts not soldered.

Figure 19. HSI oscillator accuracy characterization results for soldered parts



Software recommendations

The software flowchart must include the management of runaway conditions such as:

- Corrupted program counter
- Unexpected reset
- Critical Data corruption (for example control registers)

Prequalification trials

Most of the common failures (unexpected reset and program counter corruption) can be reproduced by manually forcing a low state on the NRST pin or the Oscillator pins for 1 second.

To complete these trials, ESD stress can be applied directly on the device, over the range of specification values. When unexpected behavior is detected, the software can be hardened to prevent unrecoverable errors occurring (see application note AN1015).

Electromagnetic Interference (EMI)

The electromagnetic field emitted by the device are monitored while a simple application is executed (toggling 2 LEDs through the I/O ports). This emission test is compliant with IEC 61967-2 standard which specifies the test board and the pin loading.

Table 49. EMI characteristics

Symbol	Parameter	Conditions	Monitored frequency band	Max vs. [f_{HSE}/f_{HCLK}]	Unit
				8/48 MHz	
S_{EMI}	Peak level	V_{DD} = 3.6 V, T_A = 25 °C, LQFP100 package compliant with IEC 61967-2	0.1 to 30 MHz	-2	dBµV
			30 to 130 MHz	27	
			130 MHz to 1 GHz	17	
			EMI Level	4	-

6.3.12 Electrical sensitivity characteristics

Based on three different tests (ESD, LU) using specific measurement methods, the device is stressed in order to determine its performance in terms of electrical sensitivity.

Electrostatic discharge (ESD)

Electrostatic discharges (a positive then a negative pulse separated by 1 second) are applied to the pins of each sample according to each pin combination. The sample size depends on the number of supply pins in the device (3 parts × (n+1) supply pins). This test conforms to the JESD22-A114/C101 standard.

6.3.17 DAC electrical specifications

Table 60. DAC characteristics

Symbol	Parameter	Min	Typ	Max	Unit	Comments
V_{DDA}	Analog supply voltage for DAC ON	2.4	-	3.6	V	-
R_{LOAD}(1)	Resistive load with buffer ON	5	-	-	kΩ	Load connected to V_{SSA}
		25	-	-	kΩ	Load connected to V_{DDA}
R_O(1)	Impedance output with buffer OFF	-	-	15	kΩ	When the buffer is OFF, the Minimum resistive load between DAC_OUT and V_{SS} to have a 1% accuracy is 1.5 MΩ
C_{LOAD}(1)	Capacitive load	-	-	50	pF	Maximum capacitive load at DAC_OUT pin (when the buffer is ON).
DAC_OUT min(1)	Lower DAC_OUT voltage with buffer ON	0.2	-	-	V	It gives the maximum output excursion of the DAC. It corresponds to 12-bit input code (0x0E0) to (0xF1C) at V_{DDA} = 3.6 V and (0x155) and (0xEAB) at V_{DDA} = 2.4 V
DAC_OUT max(1)	Higher DAC_OUT voltage with buffer ON	-	-	V_{DDA} – 0.2	V	
DAC_OUT min(1)	Lower DAC_OUT voltage with buffer OFF	-	0.5	-	mV	It gives the maximum output excursion of the DAC.
DAC_OUT max(1)	Higher DAC_OUT voltage with buffer OFF	-	-	V_{DDA} – 1LSB	V	
I_{DDA}(1)	DAC DC current consumption in quiescent mode(2)	-	-	600	µA	With no load, middle code (0x800) on the input
		-	-	700	µA	With no load, worst code (0xF1C) on the input
DNL(3)	Differential non linearity Difference between two consecutive code-1LSB)	-	-	±0.5	LSB	Given for the DAC in 10-bit configuration
		-	-	±2	LSB	Given for the DAC in 12-bit configuration
INL(3)	Integral non linearity (difference between measured value at Code i and the value at Code i on a line drawn between Code 0 and last Code 1023)	-	-	±1	LSB	Given for the DAC in 10-bit configuration
		-	-	±4	LSB	Given for the DAC in 12-bit configuration
Offset(3)	Offset error (difference between measured value at Code (0x800) and the ideal value = V_{DDA}/2)	-	-	±10	mV	-
		-	-	±3	LSB	Given for the DAC in 10-bit at V_{DDA} = 3.6 V
		-	-	±12	LSB	Given for the DAC in 12-bit at V_{DDA} = 3.6 V

6.3.18 Comparator characteristics

Table 61. Comparator characteristics

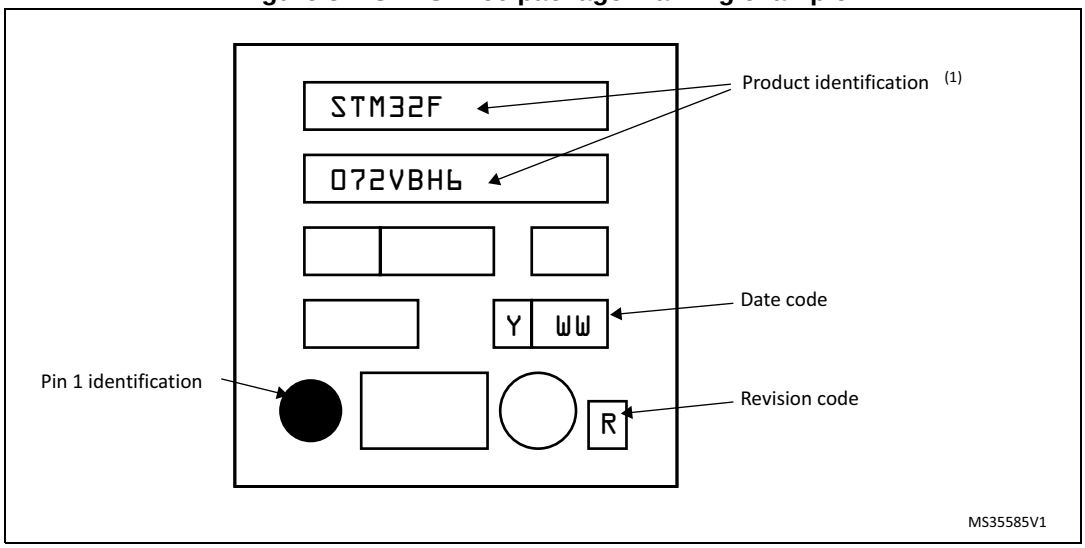
Symbol	Parameter	Conditions		Min(1)	Typ	Max(1)	Unit
V_{DDA}	Analog supply voltage	-		V_{DD}	-	3.6	V
V_{IN}	Comparator input voltage range	-		0	-	V_{DDA}	-
V_{SC}	V_{REFINT} scaler offset voltage	-		-	±5	±10	mV
t_{S_SC}	V_{REFINT} scaler startup time from power down	First V_{REFINT} scaler activation after device power on		-	-	1000 (2)	ms
		Next activations		-	-	0.2	
t_{START}	Comparator startup time	Startup time to reach propagation delay specification		-	-	60	µs
t_D	Propagation delay for 200 mV step with 100 mV overdrive	Ultra-low power mode		-	2	4.5	µs
		Low power mode		-	0.7	1.5	
		Medium power mode		-	0.3	0.6	
		High speed mode	$V_{DDA} \geq 2.7$ V	-	50	100	ns
			$V_{DDA} < 2.7$ V	-	100	240	
	Propagation delay for full range step with 100 mV overdrive	Ultra-low power mode		-	2	7	µs
		Low power mode		-	0.7	2.1	
		Medium power mode		-	0.3	1.2	
		High speed mode	$V_{DDA} \geq 2.7$ V	-	90	180	ns
			$V_{DDA} < 2.7$ V	-	110	300	
V_{offset}	Comparator offset error	-		-	±4	±10	mV
dV_{offset}/dT	Offset error temperature coefficient	-		-	18	-	µV/°C
$I_{DD(COMP)}$	COMP current consumption	Ultra-low power mode		-	1.2	1.5	µA
		Low power mode		-	3	5	
		Medium power mode		-	10	15	
		High speed mode		-	75	100	

Device marking

The following figure gives an example of topside marking orientation versus pin 1 identifier location.

Other optional marking or inset/upset marks, which identify the parts throughout supply chain operations, are not indicated below.

Figure 37. UFBGA100 package marking example



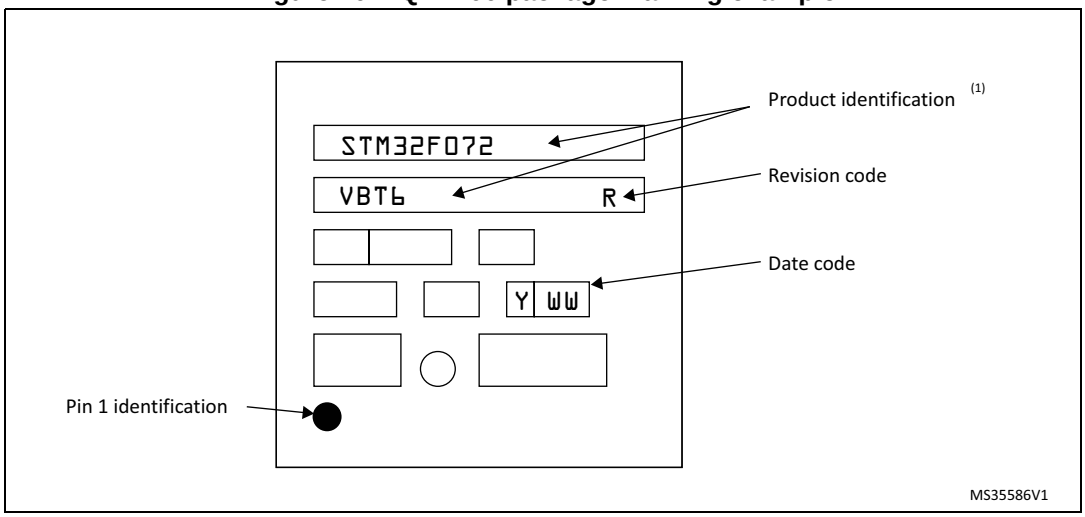
1. Parts marked as "ES", "E" or accompanied by an Engineering Sample notification letter, are not yet qualified and therefore not yet ready to be used in production and any consequences deriving from such usage will not be at ST charge. In no event, ST will be liable for any customer usage of these engineering samples in production. ST Quality has to be contacted prior to any decision to use these Engineering Samples to run qualification activity.

Device marking

The following figure gives an example of topside marking orientation versus pin 1 identifier location.

Other optional marking or inset/upset marks, which identify the parts throughout supply chain operations, are not indicated below.

Figure 40. LQFP100 package marking example



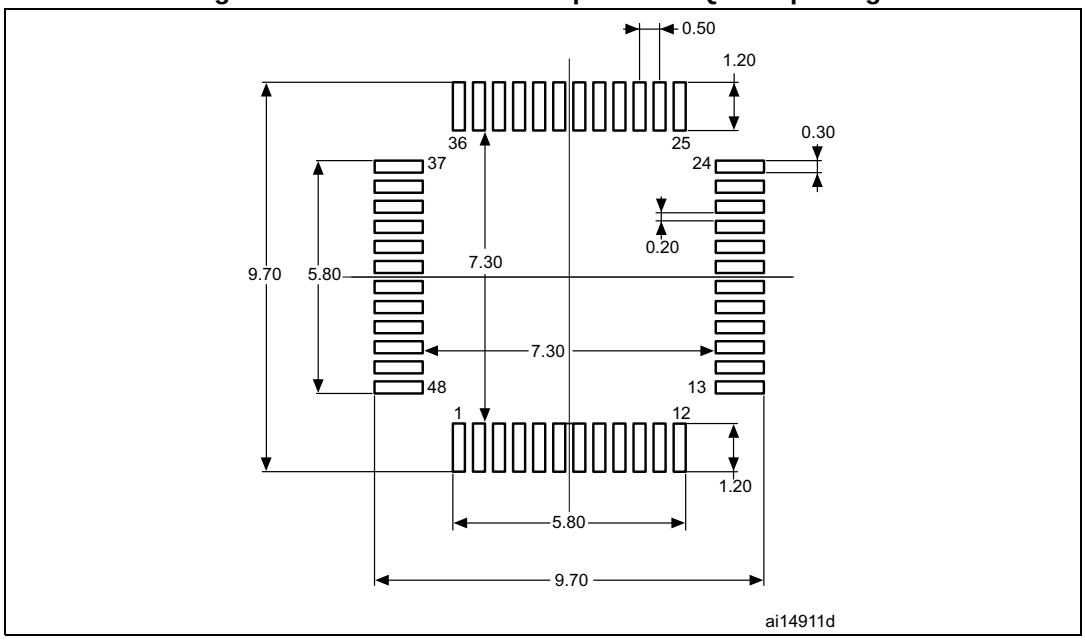
1. Parts marked as "ES", "E" or accompanied by an Engineering Sample notification letter, are not yet qualified and therefore not yet ready to be used in production and any consequences deriving from such usage will not be at ST charge. In no event, ST will be liable for any customer usage of these engineering samples in production. ST Quality has to be contacted prior to any decision to use these Engineering Samples to run qualification activity.

Table 78. LQFP48 package mechanical data

Symbol	millimeters			inches[1]		
	Min	Typ	Max	Min	Typ	Max
A	-	-	1.600	-	-	0.0630
A1	0.050	-	0.150	0.0020	-	0.0059
A2	1.350	1.400	1.450	0.0531	0.0551	0.0571
b	0.170	0.220	0.270	0.0067	0.0087	0.0106
c	0.090	-	0.200	0.0035	-	0.0079
D	8.800	9.000	9.200	0.3465	0.3543	0.3622
D1	6.800	7.000	7.200	0.2677	0.2756	0.2835
D3	-	5.500	-	-	0.2165	-
E	8.800	9.000	9.200	0.3465	0.3543	0.3622
E1	6.800	7.000	7.200	0.2677	0.2756	0.2835
E3	-	5.500	-	-	0.2165	-
e	-	0.500	-	-	0.0197	-
L	0.450	0.600	0.750	0.0177	0.0236	0.0295
L1	-	1.000	-	-	0.0394	-
k	0°	3.5°	7°	0°	3.5°	7°
ccc	-	-	0.080	-	-	0.0031

1. Values in inches are converted from mm and rounded to 4 decimal digits.

Figure 50. Recommended footprint for LQFP48 package



1. Dimensions are expressed in millimeters.